Search Notes



App	olica	tion	/Con	itrol	No.

Applicant(s)/Patent under Reexamination

10/725,378

FAN ET AL.
Art Unit

Examiner

2129

Peter Coughlan

SEARCHED					
Class	Subclass	Date	Examiner		
706	8	11/2/2007	PDC		
706	16	11/2/2007	PDC		
706	45	11/2/2007	PDC		
706	49	11/2/2007	PDC		
703	2	11/2/2007	PDC		
703	9	11/2/2007	PDC		

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
			 			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East-inductive learning, learning model, feature vector, aggregate benefit, application, purpose, function, fan wei	11/2/2007	PDC		
EastIIWang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	11/2/2007	PDC		
IEEEWang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	11/2/2007	PDC		
IEEEIIinductive learning, learning model, feature vector, aggregae benefit, application, purpose, function, fan wei	11/2/2007	PDC		
Google-inductive learning, learning model, feature vector, aggregae benefit, application, purpose, function, fan wei	11/2/2007	PDC		
DogpileWang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	11/2/2007	PDC		
InventorsWang Haixun, Yu Philip S, Fan Wei	11/2/2007	PDC		